

Special Issue

Medical Imaging and Analysis

Message from the Guest Editor

Medical imaging is an important technology in clinical applications that allows earlier diagnosis of diseases. Moreover, it helps doctors and researchers to learn more about human anatomy and physiology. This Special Issue aims to cover advances in various image modalities, such as computer tomography, magnetic resonance imaging, X-ray radiography, positron emission tomography, ultrasound imaging, imaging photoplethysmography, thermography, medical photography, multispectral imaging, elastography, and others. Contributions can be focused on conventional and unconventional image processing methods, related data analysis, and statistical tools. Review articles as well as original research articles which will bring new insights into the applied sciences of medical imaging are also welcome.

Guest Editor

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Deadline for manuscript submissions

closed (30 August 2020)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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